



<b>Features</b>	<b>Bvdss</b>	<b>Rdson</b>	<b>ID</b>
	1200V	12mΩ	150A
<ul style="list-style-type: none"> <li>➤ Low on-resistance</li> <li>➤ Fast switching speed</li> <li>➤ Fast reverse recovery</li> <li>➤ Easy to parallel</li> <li>➤ Simple to drive</li> <li>➤ Pb-free lead plating</li> <li>➤ RoHS compliant</li> </ul>	<b>Application</b>		
	<ul style="list-style-type: none"> <li>➤ Solar inverters</li> <li>➤ DC/DC converters</li> <li>➤ Switch mode power supplies</li> <li>➤ Induction heating</li> <li>➤ Motor drives</li> </ul>		
<b>Package</b>			
<p>Marking and pin assignment</p>	<p>TO247-4L top view</p>	<p>Schematic diagram</p>	

**Package Marking and Ordering Information**

Device Marking	Device	Device Package	Quantity
HLC150N120W4	HLC150N120W4	TO247-4L	30

**Absolute Maximum Ratings** ( $T_{vj}=25^{\circ}\text{C}$  unless otherwise specified)

Parameter	Symbol	Value	Unit
Drain-Source Voltage	$V_{DSS}$	1200	V
Gate-Source Voltage (DC)	$V_{GSS}$	-4 ~ 22	V
Gate-Source Surge Voltage ( $t_{surge} < 300\text{nsec}$ ) <sup>3</sup>	$V_{GSS\_surge}$	-4 ~ 26	V
Continuous Drain Current <sup>1</sup>	$T_C=25^{\circ}\text{C}$	150	A
	$T_C=100^{\circ}\text{C}$	105	A
Pulsed Drain current ( $T_C=25^{\circ}\text{C}$ ) <sup>2</sup>	$I_{D,pulse}$	490	A
Recommended drive voltage <sup>4</sup>	$V_{GS\_op}$	0/18	V
Power Dissipation	$P_D$	675	W
Virtual Junction temperature	$T_{vj}$	175	$^{\circ}\text{C}$
Range of storage temperature	$T_{STG}$	-55 ~ 175	$^{\circ}\text{C}$



## Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Thermal Resistance Junction-Case <sup>1</sup>	$R_{thJC}$	0.44	K/W

## Ordering Information

Ordering Number	Package	Pin Assignment			Packing
Halogen Free		G	D	S	
HLC150N120W4	TO247-4L	4	1	2,3	Tube

Electrical Characteristics ( $T_{VJ}=25^{\circ}\text{C}$  unless otherwise noted)

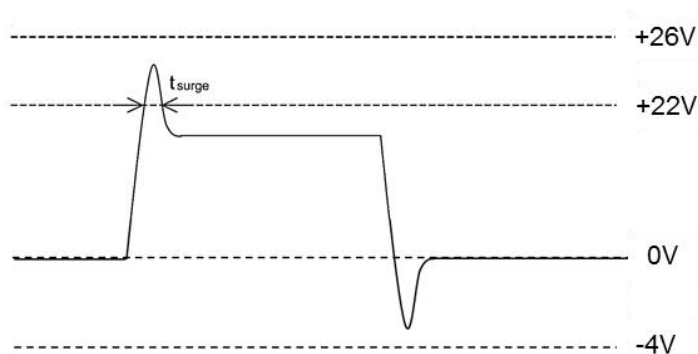
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0\text{V}, I_D=1\text{mA}, T_{VJ}=25^{\circ}\text{C}$	1200	-	-	V
		$V_{GS}=0\text{V}, I_D=1\text{mA}, T_{VJ}=-55^{\circ}\text{C}$	1200	-	-	V
Zero Gate voltage Drain current	$I_{DSS}$	$V_{DS}=1200\text{V}, V_{GS}=0\text{V}, T_{VJ}=25^{\circ}\text{C}$	-	1	10	$\mu\text{A}$
		$V_{DS}=1200\text{V}, V_{GS}=0\text{V}, T_{VJ}=150^{\circ}\text{C}$	-	2	-	
Gate - Source leakage current	$I_{GSS+}$	$V_{GS}=22\text{V}, V_{DS}=0\text{V}$	-	-	100	nA
	$I_{GSS-}$	$V_{GS}=-4\text{V}, V_{DS}=0\text{V}$	-	-	-100	
Gate-Threshold Voltage	$V_{GS(th)}$	$V_{DS}=10\text{V}, I_D=10\text{mA}$	2.3	-	3.5	V
Drain-Source On-Resistance <sup>5</sup>	$R_{DS(on)}$	$V_{GS}=18\text{V}, I_D=20\text{A}, T_{VJ}=25^{\circ}\text{C}$	-	12	16	m $\Omega$
		$V_{GS}=18\text{V}, I_D=20\text{A}, T_{VJ}=150^{\circ}\text{C}$	-	25	-	
Gate input resistance	$R_G$	f=1MHz, Open drain	-	7	-	$\Omega$
Transconductance <sup>5</sup>	gfs	$V_{DS}=10\text{V}, I_D=20\text{A}$	-	8.3	-	S
Input Capacitance	$C_{iss}$	$V_{DS}=800\text{V}, V_{GS}=0\text{V},$ f=1MHz	-	1337	-	pF
Output Capacitance	$C_{oss}$		-	76	-	
Reverse Transfer Capacitance	$C_{rss}$		-	27	-	
Effective output capacitance, energy related	$C_{o(er)}$	$V_{GS}=0\text{V}, V_{DS}=0\text{V to } 600\text{V}$	-	122	-	pF
Total Gate Charge	$Q_g$	$V_{GS}=18\text{V}, V_{DS}=600\text{V}, I_D=20\text{A}$	-	107	-	nC
Gate-Source Charge	$Q_{gs}$		-	17	-	
Gate-Drain Charge	$Q_{gd}$		-	56	-	
Turn-On Delay Time	$t_{d(on)}$	$V_{GS}=0\text{V}/+18\text{V}, V_{DS}=400\text{V},$ $R_G=0\Omega, I_D=18\text{A},$ $R_L=22\Omega$	-	21	-	ns
Rise Time	$t_r$		-	39	-	
Turn-Off Delay Time	$t_{d(off)}$		-	49	-	
Fall Time	$t_f$		-	24	-	



Turn-on switching loss <sup>5</sup>	$E_{on}$	VDS=600V, VGS=0V/18V, ID=20A, RG=0Ω, L=250uH		283		μJ
Turn-off switching loss <sup>5</sup>	$E_{off}$	Eon includes diode reverse recovery Lσ=50nH, Cσ=200pF		118		
Diode Forward Current <sup>1</sup>	$I_S$	$T_c=25^{\circ}C$	-	-	150	A
Pulsed Source Current <sup>2</sup>	$I_{SM}$		-	-	490	
Diode Forward Voltage <sup>5</sup>	$V_{SD}$	$I_S=20A, V_{GS}=0V$	-	3.2	-	V
Reverse Recovery time <sup>5</sup>	$T_{rr}$	$I_F=20A, V_R=600V, dI/dt=100A/\mu s, L_{\sigma}=50nH, C_{\sigma}=200pF$	-	25	-	ns
Reverse Recovery Charge <sup>5</sup>	$Q_{rr}$		-	115	-	nC
Peak reverse recovery current <sup>5</sup>	$I_{rrm}$		-	9	-	A

Note :

- Limited by maximum  $T_{vj}$  and for Max.  $R_{thJC}$ .
- $PW \leq 10\mu s$ , Duty cycle  $\leq 1\%$ .
- Example of acceptable  $V_{GS}$  waveform.



- Please be advised not to use SiC-MOSFETs with  $V_{es}$  below 13V as doing so may cause thermal runaway.
- Pulsed.



### Typical Performance Characteristics

Fig.1 Power Dissipation Derating Curve

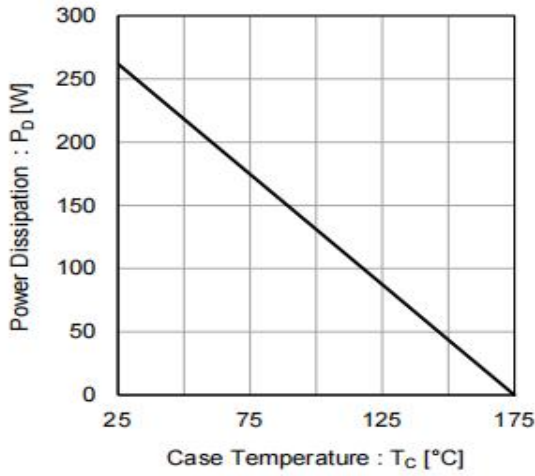


Fig.2 Maximum Safe Operating Area

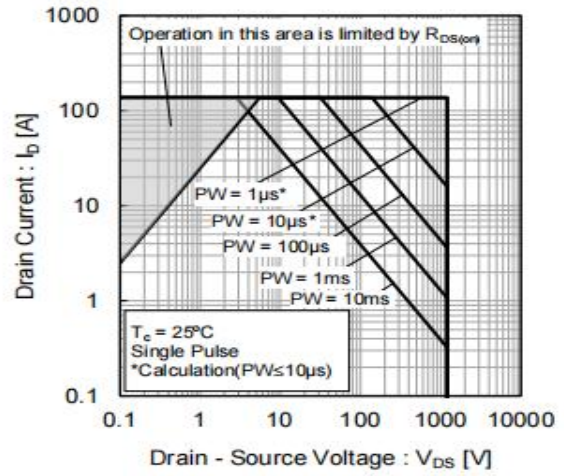


Fig.3 Typical Transient Thermal Resistance vs. Pulse Width

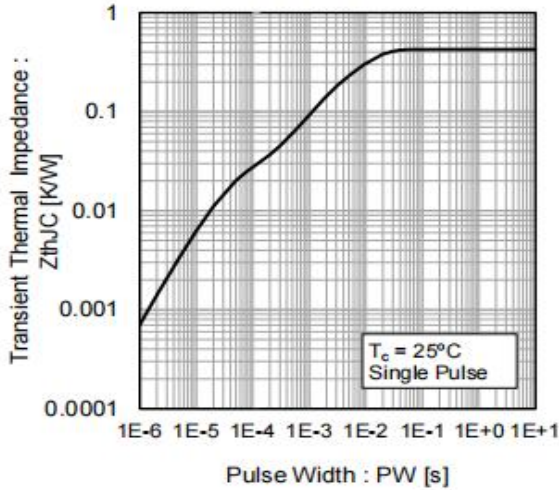


Fig.4 Typical Output Characteristics(I)

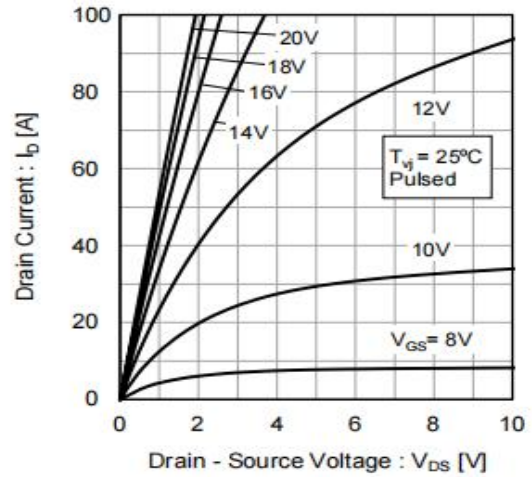


Fig.5 Typical Output Characteristics(II)

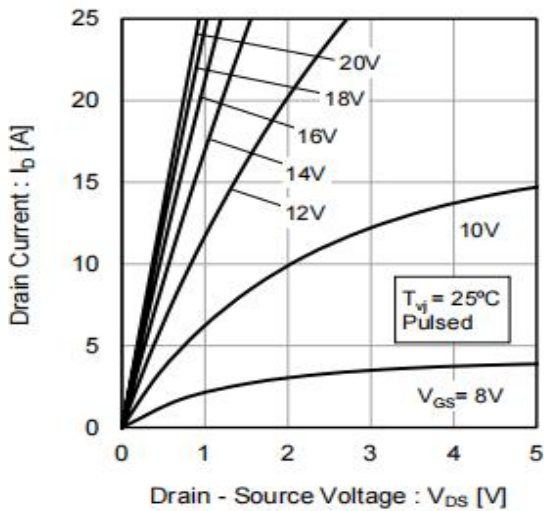


Fig.6  $T_{vj} = 25^\circ C$  3rd Quadrant Characteristics

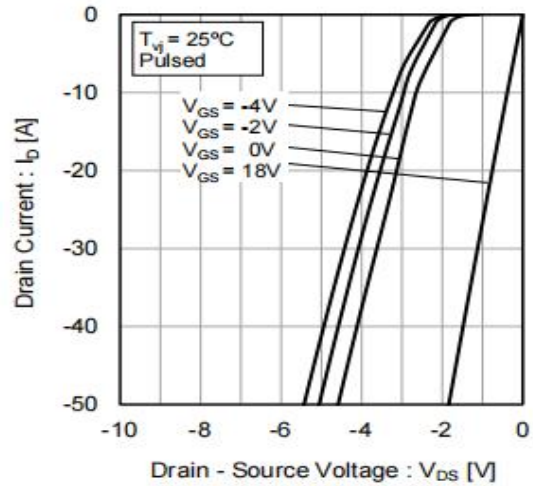




Fig.7  $T_{vj} = 150^{\circ}\text{C}$  Typical Output Characteristics(I)

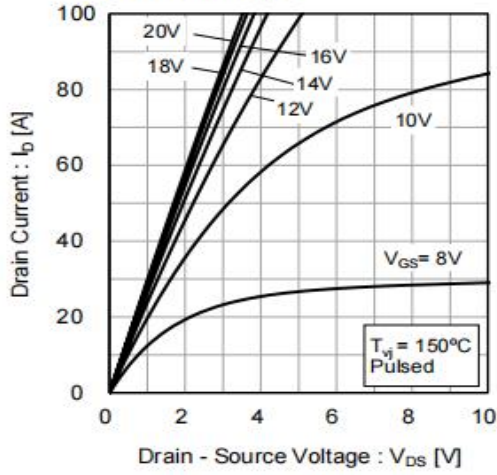


Fig.8  $T_{vj} = 150^{\circ}\text{C}$  Typical Output Characteristics(II)

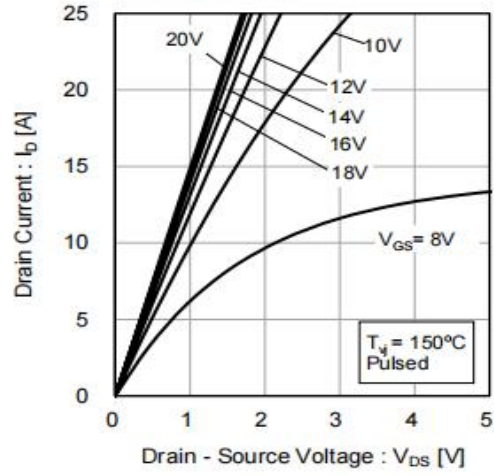


Fig.9  $T_{vj} = 150^{\circ}\text{C}$  3rd Quadrant Characteristics

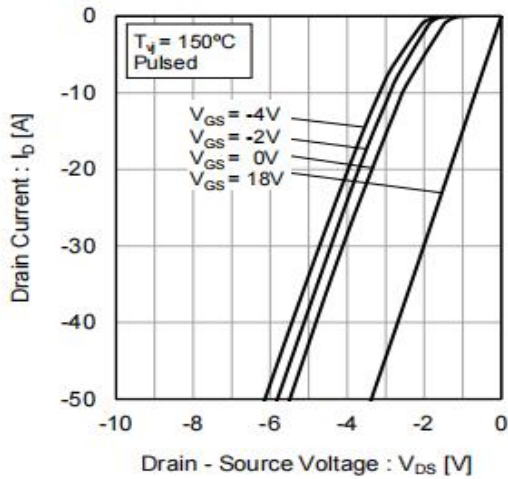


Fig.10 Body Diode Forward Voltage vs. Gate - Source Voltage

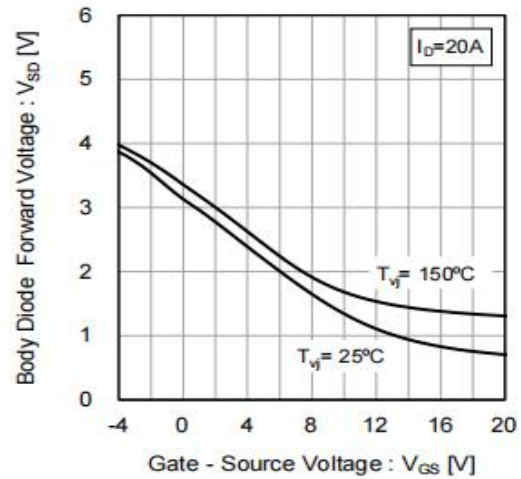


Fig.11 Typical Transfer Characteristics (I)

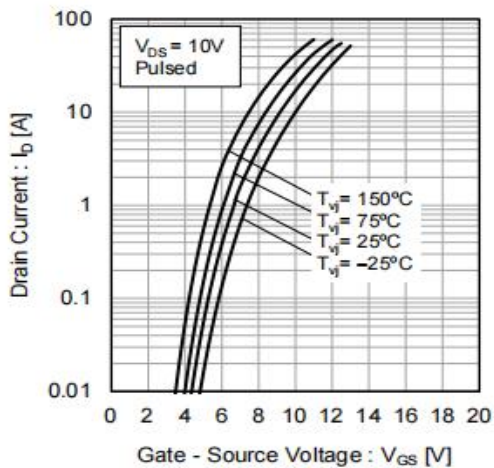


Fig.12 Typical Transfer Characteristics (II)

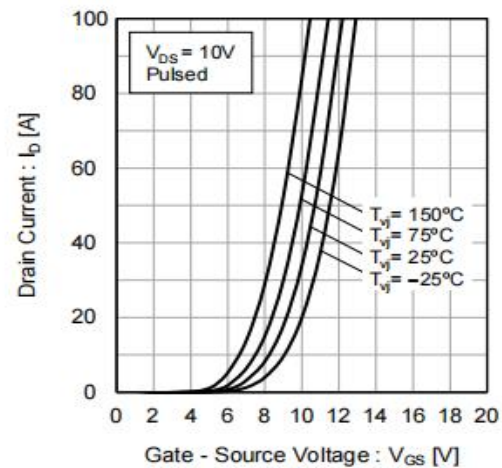




Fig.13 Gate Threshold Voltage vs. Junction Temperature

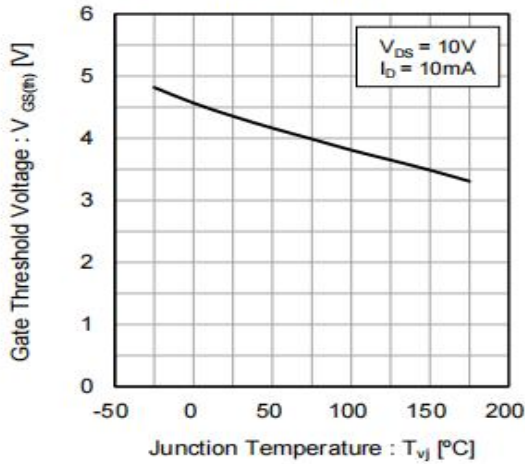


Fig.14 Transconductance vs. Drain Current

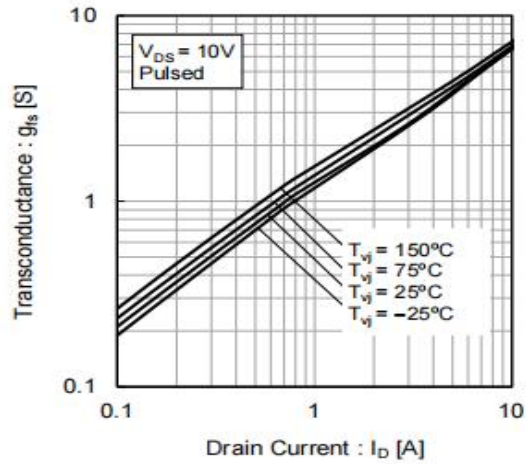


Fig.15 Static Drain - Source On - State Resistance vs. Gate - Source Voltage

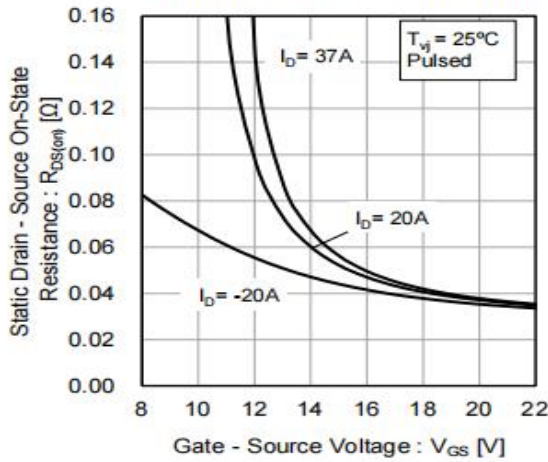


Fig.16 Static Drain - Source On - State Resistance vs. Junction Temperature

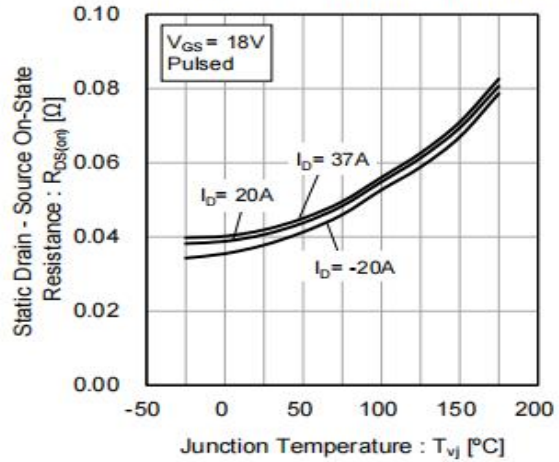


Fig.17 Static Drain - Source On - State Resistance vs. Drain Current

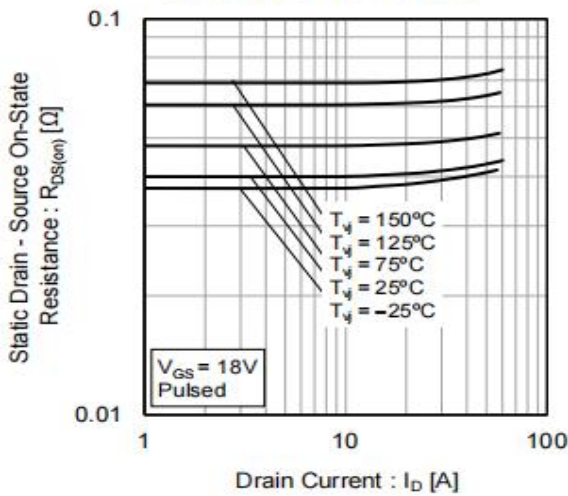


Fig.18 Normalized Drain - Source Breakdown Voltage vs. Junction Temperature

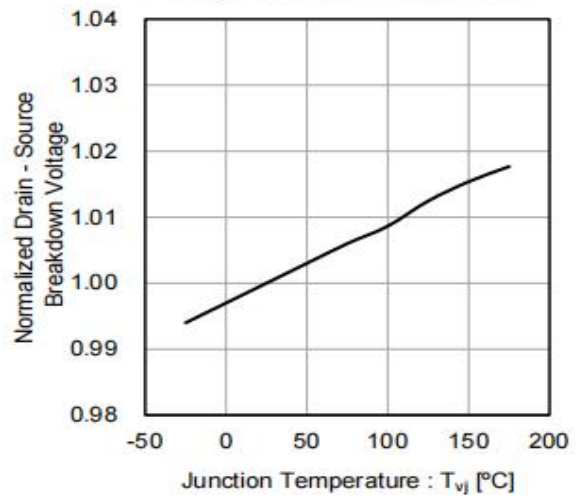




Fig.19 Typical Capacitance vs. Drain - Source Voltage

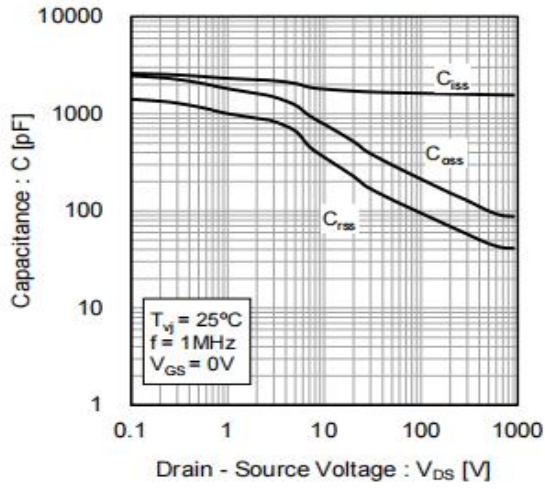


Fig.20  $C_{oss}$  Stored Energy

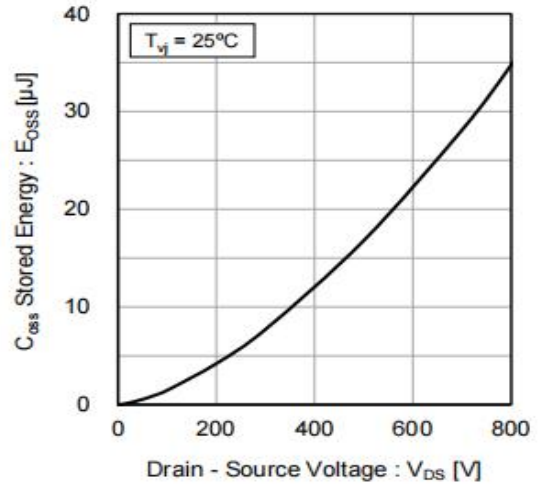
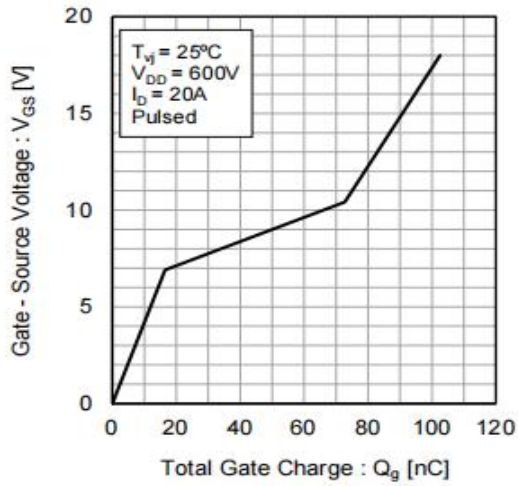
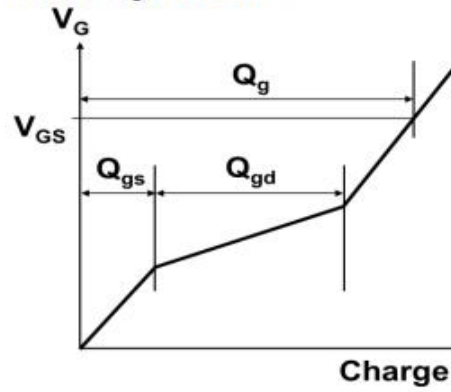


Fig.21 Dynamic Input Characteristics



\*Gate Charge Waveform





Test Circuit and Waveform

Fig.1-1 Gate Charge and Switching Time Measurement Circuit

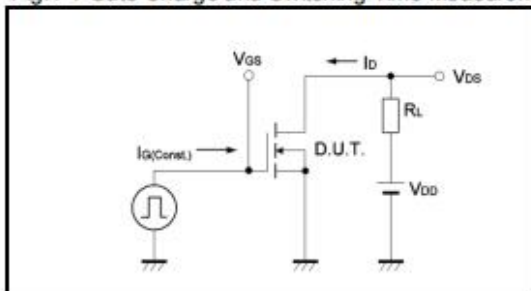


Fig.1-2 Waveforms for Switching Time

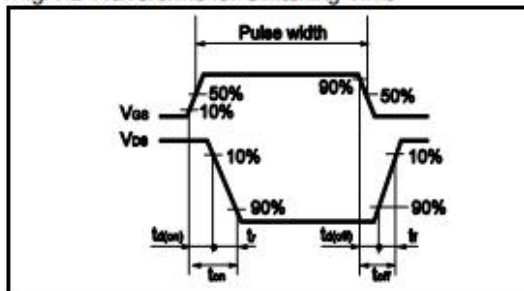


Fig.2-1 Switching Energy Measurement Circuit

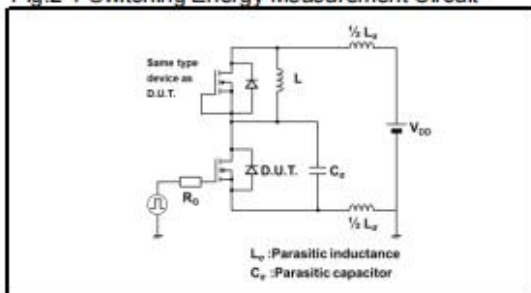


Fig.2-2 Waveforms for Switching Energy Loss

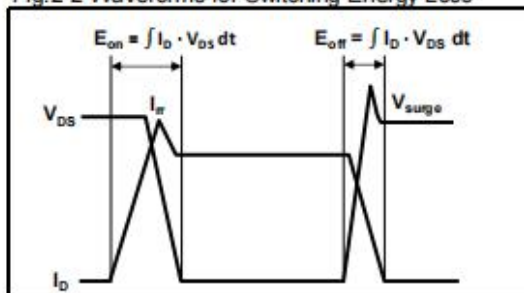


Fig.3-1 Reverse Recovery Time Measurement Circuit

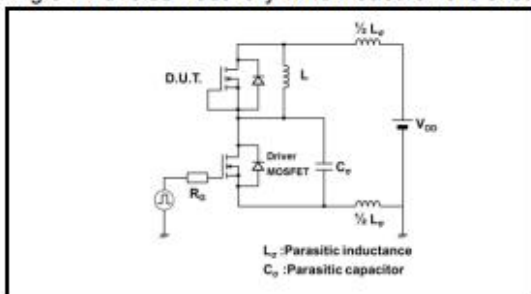
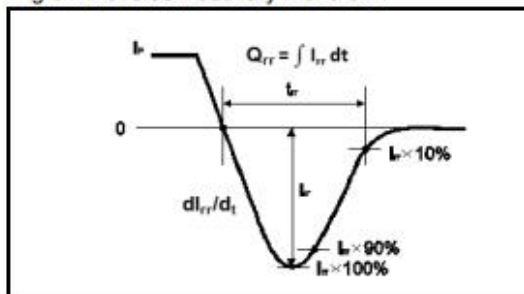
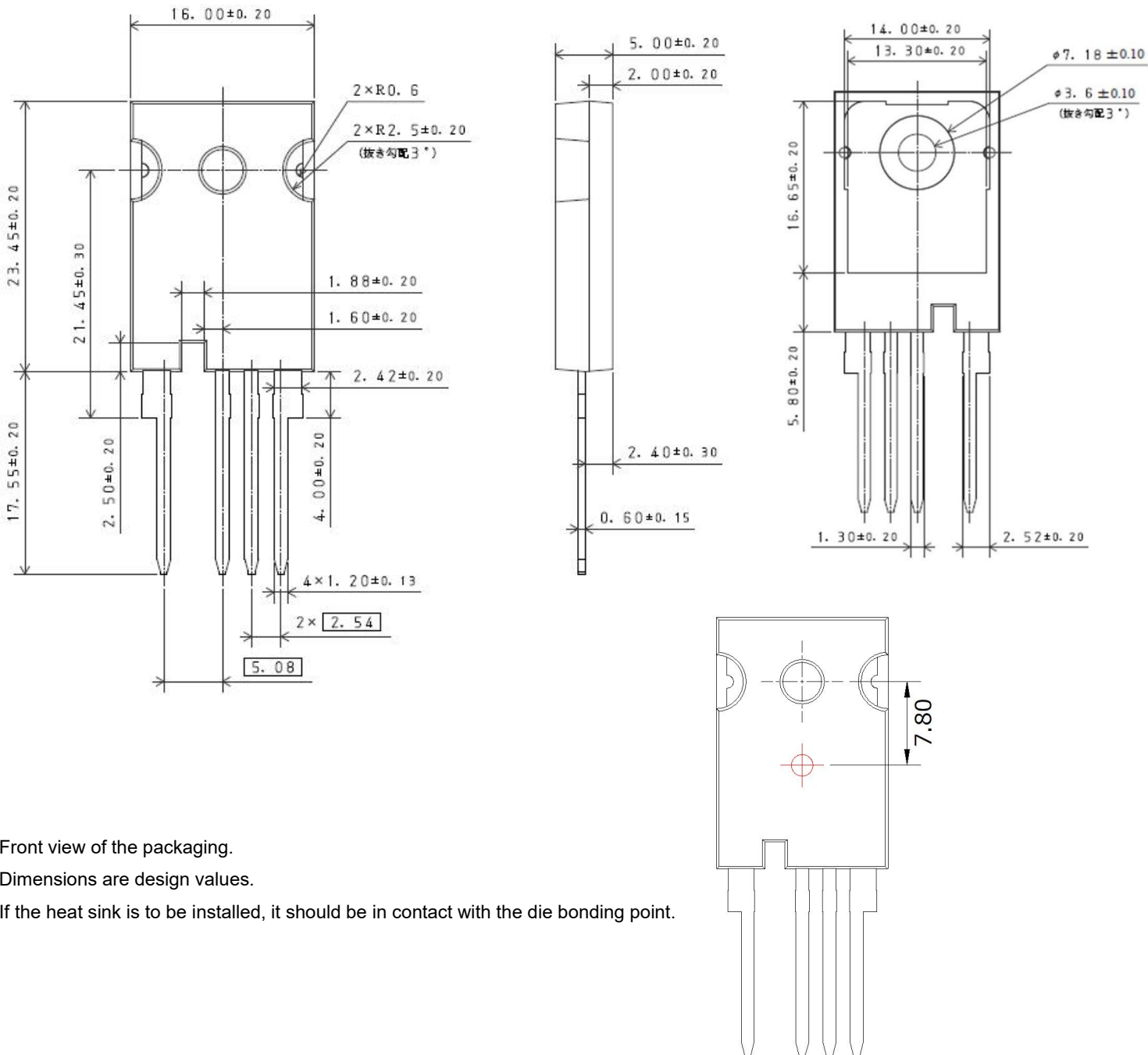


Fig.3-2 Reverse Recovery Waveform





Package Dimensions TO247-4L



- Front view of the packaging.
- Dimensions are design values.
- If the heat sink is to be installed, it should be in contact with the die bonding point.

Unit: mm



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